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Intel - 5SGXEA5K3F40C3N Datasheet



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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	185000
Number of Logic Elements/Cells	490000
Total RAM Bits	46080000
Number of I/O	696
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1517-BBGA, FCBGA
Supplier Device Package	1517-FBGA (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgxea5k3f40c3n

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Table 5 lists the maximum allowed input overshoot voltage and the duration of the overshoot voltage as a percentage of device lifetime. The maximum allowed overshoot duration is specified as a percentage of high time over the lifetime of the device. A DC signal is equivalent to 100% of the duty cycle. For example, a signal that overshoots to 3.95 V can be at 3.95 V for only ~21% over the lifetime of the device; for a device lifetime of 10 years, the overshoot duration amounts to ~2 years.

		saring transitions		
Symbol	Description	Condition (V)	Overshoot Duration as % @ T _J = 100°C	Unit
		3.8	100	%
		3.85	64	%
		3.9	36	%
		3.95	21	%
Vi (AC)	AC input voltage	4	12	%
		4.05	7	%
		4.1	4	%
		4.15	2	%
		4.2	1	%

Table 5. Maximum Allowed Overshoot During Transitions

Figure 1. Stratix V Device Overshoot Duration



Symbol	Description	Condition	Min ⁽⁴⁾	Тур	Max ⁽⁴⁾	Unit
t _{RAMP}	Power supply ramp time	Standard POR	200 µs	_	100 ms	—
		Fast POR	200 µs		4 ms	

Table 6. Recommended Operating Conditions for Stratix V Devices (Part 2 of 2)

Notes to Table 6:

(1) V_{CCPD} must be 2.5 V when V_{CCI0} is 2.5, 1.8, 1.5, 1.35, 1.25 or 1.2 V. V_{CCPD} must be 3.0 V when V_{CCI0} is 3.0 V.

(2) If you do not use the design security feature in Stratix V devices, connect V_{CCBAT} to a 1.2- to 3.0-V power supply. Stratix V power-on-reset (POR) circuitry monitors V_{CCBAT}. Stratix V devices will not exit POR if V_{CCBAT} stays at logic low.

(3) C2L and I2L can also be run at 0.90 V for legacy boards that were designed for the C2 and I2 speed grades.

(4) The power supply value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

Table 7 lists the transceiver power supply recommended operating conditions for Stratix V GX, GS, and GT devices.

Table 7. Recommended Transceiver Power Supply Operating Conditions for Stratix V GX, GS, and GT Devices (Part 1 of 2)

Symbol	Description	Devices	Minimum ⁽⁴⁾	Typical	Maximum ⁽⁴⁾	Unit	
V _{CCA GXBL}	Transceiver channel PLL power supply (left		2.85	3.0	3.15	V	
(1), (3)	side)	un, us, ui	2.375	2.5	2.625	v	
V _{CCA_GXBR}	Transceiver channel PLL power supply (right	CV CS	2.85	3.0	3.15	V	
(1), (3)	side)	ux, us	2.375	2.5	2.625	v	
V _{CCA_GTBR}	Transceiver channel PLL power supply (right side)	GT	2.85	3.0	3.15	V	
	Transceiver hard IP power supply (left side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V	
V _{CCHIP_L}	Transceiver hard IP power supply (left side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V	
	Transceiver hard IP power supply (right side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V	
V _{CCHIP_R}	Transceiver hard IP power supply (right side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V	
	Transceiver PCS power supply (left side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V	
V _{CCHSSI_L}	Transceiver PCS power supply (left side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V	
	Transceiver PCS power supply (right side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V	
V _{CCHSSI_R}	Transceiver PCS power supply (right side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V	
			0.82	0.85	0.88		
V _{CCR_GXBL}	Receiver analog nower supply (left side)		0.87	0.90	0.93	V	
(2) _	Therefore analog power supply (left Slue)	GX, GS, G1	0.97	1.0	1.03		
			1.03	1.05	1.07		

Symbol	Description	Devices	Minimum ⁽⁴⁾	Typical	Maximum ⁽⁴⁾	Unit	
			0.82	0.85	0.88		
V _{CCR_GXBR}	Receiver analog power supply (right side)		0.87	0.90	0.93	v	
(2)	neceiver analog power supply (right side)	ux, us, ui	0.97	1.0	1.03	v	
			1.03	1.05	1.07		
V _{CCR_GTBR}	Receiver analog power supply for GT channels (right side)	GT	1.02	1.05	1.08	V	
			0.82	0.85	0.88		
V _{CCT_GXBL}	Transmitter analog newer supply (left side)		0.87	0.90	0.93	V	
	Transmitter analog power supply (left side)	un, uo, ui	0.97	1.0	1.03		
			1.03	1.05	1.07		
		GX, GS, GT	0.82	0.85	0.88		
V _{CCT GXBR}	Transmitter analog newer supply (right side)		0.87	0.90	0.93	v	
(2) _	Transmitter analog power supply (light side)		0.97	1.0	1.03	V	
(2) - V V _{CCR_GTBR} V _{CCT_GXBL} (2) V _{CCT_GXBR} V _{CCL_GTBR} V _{CCL_GXBL} V _{CCH_GXBL}			1.03	1.05	1.07		
V_{CCT_GTBR}	Transmitter analog power supply for GT channels (right side)	GT	1.02	1.05	1.08	V	
V_{CCL_GTBR}	Transmitter clock network power supply	GT	1.02	1.05	1.08	V	
V _{CCH_GXBL}	Transmitter output buffer power supply (left side)	GX, GS, GT	1.425	1.5	1.575	V	
V _{CCH_GXBR}	Transmitter output buffer power supply (right side)	GX, GS, GT	1.425	1.5	1.575	V	

Table 7.	Recommended Transceiver Power Supply Operating Conditions for Stratix V GX ,	GS , and GT Devices
(Part 2	of 2)	

Notes to Table 7:

(1) This supply must be connected to 3.0 V if the CMU PLL, receiver CDR, or both, are configured at a base data rate > 6.5 Gbps. Up to 6.5 Gbps, you can connect this supply to either 3.0 V or 2.5 V.

(2) Refer to Table 8 to select the correct power supply level for your design.

(3) When using ATX PLLs, the supply must be 3.0 V.

(4) This value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

			Resistance Tolerance				
Symbol	Description	Conditions	C1	C2,I2	C3, I3, I3YY	C4, I4	Unit
50-Ω R _S	Internal series termination without calibration (50- Ω setting)	$V_{CCIO} = 1.8$ and 1.5 V	±30	±30	±40	±40	%
50-Ω R _S	Internal series termination without calibration (50- Ω setting)	V _{CCI0} = 1.2 V	±35	±35	±50	±50	%
100-Ω R _D	Internal differential termination (100- Ω setting)	V _{CCPD} = 2.5 V	±25	±25	±25	±25	%

Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 2 of 2)

Calibration accuracy for the calibrated series and parallel OCTs are applicable at the moment of calibration. When voltage and temperature conditions change after calibration, the tolerance may change.

OCT calibration is automatically performed at power-up for OCT-enabled I/Os. Table 13 lists the OCT variation with temperature and voltage after power-up calibration. Use Table 13 to determine the OCT variation after power-up calibration and Equation 1 to determine the OCT variation without recalibration.

Equation 1. OCT Variation Without Recalibration for Stratix V Devices (1), (2), (3), (4), (5), (6)

$$R_{OCT} \,=\, R_{SCAL} \Big(1 + \langle \frac{dR}{dT} \times \Delta T \rangle \pm \langle \frac{dR}{dV} \times \Delta V \rangle \Big) \label{eq:ROCT}$$

Notes to Equation 1:

- (1) The R_{OCT} value shows the range of OCT resistance with the variation of temperature and V_{CCIO} .
- (2) R_{SCAL} is the OCT resistance value at power-up.
- (3) ΔT is the variation of temperature with respect to the temperature at power-up.
- (4) ΔV is the variation of voltage with respect to the V_{CCIO} at power-up.
- (5) dR/dT is the percentage change of R_{SCAL} with temperature.
- (6) dR/dV is the percentage change of $\mathsf{R}_{\mathsf{SCAL}}$ with voltage.

Table 13 lists the on-chip termination variation after power-up calibration.

Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 1 of 2)
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Symbol	Description	V _{CCIO} (V)	Typical	Unit
		3.0	0.0297	
	OCT variation with voltage without recalibration	2.5	0.0344	%/mV
dR/dV		1.8	0.0499	
		1.5	0.0744	1
		1.2	0.1241	

I/0	V _{CCIO} (V)			V _{DIF(}	_{DC)} (V)	V _{X(AC)} (V)				V _{CM(DC)} (V	V _{DIF(AC)} (V)		
Standard	Min	Тур	Max	Min	Max	Min	Тур	Max	Min	Тур	Max	Min	Max
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V _{CCI0} + 0.3	_	0.5* V _{CCI0}	_	0.4* V _{CCIO}	0.5* V _{CCIO}	0.6* V _{CCI0}	0.3	V _{CCI0} + 0.48
HSUL-12	1.14	1.2	1.3	0.26	0.26	0.5*V _{CCI0} - 0.12	0.5* V _{CCI0}	0.5*V _{CCI0} + 0.12	0.4* V _{CCIO}	0.5* V _{CCIO}	0.6* V _{CCIO}	0.44	0.44

Table 21. Differential HSTL and HSUL I/O Standards for Stratix V Devices (Part 2 of 2)

Table 22. Differential I/O Standard Specifications for Stratix V Devices (7)

I/O	V _{CCI0} (V) ⁽¹⁰⁾			V _{ID} (mV) ⁽⁸⁾		V _{ICM(DC)} (V)			V _{od} (V) ⁽⁶⁾			V _{OCM} (V) <i>(6)</i>			
Standard	Min	Тур	Max	Min	Condition	Max	Min	Condition	Max	Min	Тур	Max	Min	Тур	Max
PCML	Trar	nsmitte	er, receiv transmi	ver, and itter, rec	input referer ceiver, and re	nce cloo eference	ck pins e clock	of the high-s I/O pin speci	peed tra fications	nsceiver , refer to	rs use o Table	the PC e 23 on	ML I/O s page 18	standard 3.	. For
2.5 V	2 375	25	2 625	100	V _{CM} =	_	0.05	D _{MAX} ≤ 700 Mbps	1.8	0.247	_	0.6	1.125	1.25	1.375
LVDS ⁽¹⁾	2.575	2.0	2.025	100	1.25 V	_	1.05	D _{MAX} > 700 Mbps	1.55	0.247	_	0.6	1.125	1.25	1.375
BLVDS (5)	2.375	2.5	2.625	100	_	_	_	_	_	_	_	—	_	—	
RSDS (HIO) ⁽²⁾	2.375	2.5	2.625	100	V _{CM} = 1.25 V	_	0.3	_	1.4	0.1	0.2	0.6	0.5	1.2	1.4
Mini- LVDS (HIO) ⁽³⁾	2.375	2.5	2.625	200	_	600	0.4	_	1.325	0.25	_	0.6	1	1.2	1.4
LVPECL (4	_	_	_	300	_		0.6	D _{MAX} ≤ 700 Mbps	1.8		_	_	_	_	_
), (9)				300			1	D _{MAX} > 700 Mbps	1.6						

Notes to Table 22:

(1) For optimized LVDS receiver performance, the receiver voltage input range must be between 1.0 V to 1.6 V for data rates above 700 Mbps, and 0 V to 1.85 V for data rates below 700 Mbps.

(2) For optimized RSDS receiver performance, the receiver voltage input range must be between 0.25 V to 1.45 V.

(3) For optimized Mini-LVDS receiver performance, the receiver voltage input range must be between 0.3 V to 1.425 V.

- (4) For optimized LVPECL receiver performance, the receiver voltage input range must be between 0.85 V to 1.75 V for data rate above 700 Mbps and 0.45 V to 1.95 V for data rate below 700 Mbps.
- (5) There are no fixed V_{ICM} , V_{OD} , and V_{OCM} specifications for BLVDS. They depend on the system topology.
- (6) RL range: $90 \le RL \le 110 \Omega$.
- (7) The 1.4-V and 1.5-V PCML transceiver I/O standard specifications are described in "Transceiver Performance Specifications" on page 18.
- (8) The minimum VID value is applicable over the entire common mode range, VCM.
- (9) LVPECL is only supported on dedicated clock input pins.
- (10) Differential inputs are powered by VCCPD which requires 2.5 V.

Power Consumption

Altera offers two ways to estimate power consumption for a design—the Excel-based Early Power Estimator and the Quartus[®] II PowerPlay Power Analyzer feature.

Switching Characteristics

This section provides performance characteristics of the Stratix V core and periphery blocks.

These characteristics can be designated as Preliminary or Final.

- Preliminary characteristics are created using simulation results, process data, and other known parameters. The title of these tables show the designation as "Preliminary."
- Final numbers are based on actual silicon characterization and testing. The numbers reflect the actual performance of the device under worst-case silicon process, voltage, and junction temperature conditions. There are no designations on finalized tables.

Transceiver Performance Specifications

This section describes transceiver performance specifications.

Table 23 lists the Stratix V GX and GS transceiver specifications.

Table 23.	Transceiver 3	Specifications	for Stratix	V GX	and GS	Devices	(1)	(Part 1	nf 7	۱
Table 20.	TIANSUCIACI	opeonitionationa	IUI UIIAIIA	I UA	anu uu	DEVICES	• •	(1 61 6 1		

Symbol/	Conditions	Tra	nsceive Grade	r Speed 1	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
Reference Clock											
Supported I/O	Dedicated reference clock pin	1.2-V PCML, 1.4-V PCML, 1.5-V PCML, 2.5-V PCML, Differential LVPECL, LVDS, and HCSL									
Standards	RX reference clock pin		1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS								
Input Reference Clock Frequency (CMU PLL) ⁽⁸⁾	_	40		710	40	_	710	40	_	710	MHz
Input Reference Clock Frequency (ATX PLL) ⁽⁸⁾		100		710	100		710	100		710	MHz
Rise time	Measure at ±60 mV of differential signal ⁽²⁶⁾			400	_		400			400	ns
Fall time	Measure at ±60 mV of differential signal ⁽²⁶⁾		_	400	_		400			400	μσ
Duty cycle		45		55	45		55	45	—	55	%
Spread-spectrum modulating clock frequency	PCI Express® (PCIe [®])	30		33	30		33	30	_	33	kHz

Table 26 shows the approximate maximum data rate using the 10G PCS.

Mada (2)	Transceiver	PMA Width	64	40	40	40	32	32			
mode ""	Speed Grade	PCS Width	64	66/67	50	40	64/66/67	32			
	1	C1, C2, C2L, I2, I2L core speed grade	14.1	14.1	10.69	14.1	13.6	13.6			
	2	C1, C2, C2L, I2, I2L core speed grade	12.5	12.5	10.69	12.5	12.5	12.5			
	Z	C3, I3, I3L core speed grade	12.5	12.5	10.69	12.5	10.88	10.88			
FIFO or Register		C1, C2, C2L, I2, I2L core speed grade									
	3	C3, I3, I3L core speed grade	8.5 Gbps								
	5	C4, I4 core speed grade									
		I3YY core speed grade	10.3125 Gbps								

Notes to Table 26:

(1) The maximum data rate is in Gbps.

(2) The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.





Figure 3 shows the Stratix V AC gain curves for GX channels.

Figure 3. AC Gain Curves for GX Channels (full bandwidth)

Stratix V GT devices contain both GX and GT channels. All transceiver specifications for the GX channels not listed in Table 28 are the same as those listed in Table 23.

Table 28 lists the Stratix V GT transceiver specifications.

Symbol/	Conditions	S	Transceive peed Grade	2	S	Fransceive Deed Grade	r 3	Unit
Description		Min	Тур	Max	Min	Тур	Max	
Differential on-chip termination resistors ⁽⁷⁾	GT channels		100	_	_	100	_	Ω
	85- Ω setting	_	85 ± 30%	_	_	85 ± 30%	_	Ω
Differential on-chip	100-Ω setting	_	100 ± 30%	_	_	100 ± 30%	_	Ω
for GX channels ⁽¹⁹⁾	120-Ω setting	_	120 ± 30%	_	—	120 ± 30%	—	Ω
	150-Ω setting		150 ± 30%	_	_	150 ± 30%	_	Ω
V _{ICM} (AC coupled)	GT channels	_	650	_	—	650	—	mV
	VCCR_GXB = 0.85 V or 0.9 V	_	600	_	_	600	_	mV
VICM (AC and DC coupled) for GX Channels	VCCR_GXB = 1.0 V full bandwidth	_	700		_	700	_	mV
	VCCR_GXB = 1.0 V half bandwidth	_	750	_	_	750	_	mV
t _{LTR} ⁽⁹⁾	—	_	—	10	—	—	10	μs
t _{LTD} ⁽¹⁰⁾		4			4	_	_	μs
t _{LTD_manual} ⁽¹¹⁾		4	_		4	_	_	μs
t _{LTR_LTD_manual} ⁽¹²⁾	—	15	—	_	15	—	—	μs
Run Lenath	GT channels		—	72	—	—	72	CID
	GX channels				(8)			
CDR PPM	GT channels	_	—	1000	—	—	1000	± PPM
	GX channels				(8)			
Programmable	GT channels			14		_	14	dB
(AC Gain) ⁽⁵⁾	GX channels				(8)			
Programmable	GT channels	_		7.5	_		7.5	dB
DC gain ⁽⁶⁾	GX channels				(8)			
Differential on-chip termination resistors ⁽⁷⁾	GT channels	_	100	—	_	100	_	Ω
Transmitter								
Supported I/O Standards	_	1.4-V and 1.5-V PCML						
Data rate (Standard PCS)	GX channels	600	_	8500	600		8500	Mbps
Data rate (10G PCS)	GX channels	600		12,500	600		12,500	Mbps

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 3 of 5)⁽¹⁾

Symbol	Parameter	Min	Тур	Max	Unit
+ (3) (4)	Input clock cycle-to-cycle jitter ($f_{REF} \ge 100 \text{ MHz}$)			0.15	UI (p-p)
LINCCJ (0), (1)	Input clock cycle-to-cycle jitter (f _{REF} < 100 MHz)	-750		+750	ps (p-p)
+ (5)	Period Jitter for dedicated clock output (f_{OUT} \geq 100 MHz)	_	_	175 ⁽¹⁾	ps (p-p)
CUTPJ_DC	Period Jitter for dedicated clock output (f _{OUT} < 100 MHz)	_	_	17.5 ⁽¹⁾	mUI (p-p)
+ (5)	Period Jitter for dedicated clock output in fractional PLL ($f_{OUT} \ge 100 \text{ MHz}$)	_	_	250 ⁽¹¹⁾ , 175 ⁽¹²⁾	ps (p-p)
^L FOUTPJ_DC	Period Jitter for dedicated clock output in fractional PLL (f _{OUT} < 100 MHz)	_	_	25 ⁽¹¹⁾ , 17.5 ⁽¹²⁾	mUI (p-p)
+ (5)	Cycle-to-Cycle Jitter for a dedicated clock output ($f_{\text{OUT}} \geq 100 \text{ MHz})$		_	175	ps (p-p)
COUTCCJ_DC	Cycle-to-Cycle Jitter for a dedicated clock output $(f_{OUT} < 100 \text{ MHz})$		_	17.5	mUI (p-p)
+ (5)	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ($f_{OUT} \ge 100 \text{ MHz}$)		_	250 ⁽¹¹⁾ , 175 ⁽¹²⁾	ps (p-p)
FOUTCCJ_DC	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ($f_{OUT} < 100 \text{ MHz}$)+		_	25 ⁽¹¹⁾ , 17.5 ⁽¹²⁾	mUI (p-p)
t _{outpj 10} (5),	Period Jitter for a clock output on a regular I/O in integer PLL ($f_{OUT} \ge 100 \text{ MHz}$)		_	600	ps (p-p)
(8)	Period Jitter for a clock output on a regular I/O $(f_{OUT} < 100 \text{ MHz})$		_	60	mUI (p-p)
t _{foutpj 10} ^{(5),}	Period Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} \ge 100 \text{ MHz}$)	_	_	600 ⁽¹⁰⁾	ps (p-p)
(8), (11)	Period Jitter for a clock output on a regular I/O in fractional PLL (f _{OUT} < 100 MHz)	_	_	60 ⁽¹⁰⁾	mUI (p-p)
t _{outccj_io} (5),	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ($f_{OUT} \geq 100 \mbox{ MHz})$	_	_	600	ps (p-p)
(8)	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL (f _{OUT} < 100 MHz)	_	_	60 ⁽¹⁰⁾	mUI (p-p)
t _{FOUTCCJ 10} (5),	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} \ge 100$ MHz)		_	600 ⁽¹⁰⁾	ps (p-p)
(8), (11)	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL (f _{OUT} < 100 MHz)	_	_	60	mUI (p-p)
t _{CASC OUTPJ DC}	Period Jitter for a dedicated clock output in cascaded PLLs ($f_{OUT} \ge 100 \text{ MHz}$)	_	_	175	ps (p-p)
(5), (6)	Period Jitter for a dedicated clock output in cascaded PLLs (f_{OUT} < 100 MHz)	_	_	17.5	mUI (p-p)
f _{DRIFT}	Frequency drift after PFDENA is disabled for a duration of 100 μs		_	±10	%
dK _{BIT}	Bit number of Delta Sigma Modulator (DSM)	8	24	32	Bits
k _{VALUE}	Numerator of Fraction	128	8388608	2147483648	—

Table 31. PLL Specifications for Stratix V Devices (Part 2 of 3)

Mode	C1	C2, C2L	12, 12L	C3	13, 13L, 13YY	C4	14	Unit	
Modes using Three DSPs									
One complex 18 x 25	425	425	415	340	340	275	265	MHz	
Modes using Four DSPs									
One complex 27 x 27	465	465	465	380	380	300	290	MHz	

Table 32. Block Performance Specifications for Stratix V DSP Devices (Part 2 of 2)

Memory Block Specifications

Table 33 lists the Stratix V memory block specifications.

Table 33. Memory Block Performance Specifications for Stratix V Devices ^{(1), (2)} (Part 1 of 2)

		Resources Used		Performance							
Memory	Mode	ALUTS	Memory	C1	C2, C2L	C3	C4	12, 12L	13, 13L, 13YY	14	Unit
	Single port, all supported widths	0	1	450	450	400	315	450	400	315	MHz
MLAR	Simple dual-port, x32/x64 depth	0	1	450	450	400	315	450	400	315	MHz
WILAD	Simple dual-port, x16 depth ⁽³⁾	0	1	675	675	533	400	675	533	400	MHz
	ROM, all supported widths	0	1	600	600	500	450	600	500	450	MHz

		Resources Used			Performance							
Memory	Mode	ALUTS	Memory	C1	C2, C2L	C3	C4	12, 12L	13, 13L, 13YY	14	Unit	
	Single-port, all supported widths	0	1	700	700	650	550	700	500	450	MHz	
	Simple dual-port, all supported widths	0	1	700	700	650	550	700	500	450	MHz	
	Simple dual-port with the read-during-write option set to Old Data , all supported widths	0	1	525	525	455	400	525	455	400	MHz	
M20K Block	Simple dual-port with ECC enabled, 512 × 32	0	1	450	450	400	350	450	400	350	MHz	
	Simple dual-port with ECC and optional pipeline registers enabled, 512 × 32	0	1	600	600	500	450	600	500	450	MHz	
	True dual port, all supported widths	0	1	700	700	650	550	700	500	450	MHz	
	ROM, all supported widths	0	1	700	700	650	550	700	500	450	MHz	

Table 33. Memory Block Performance Specifications for Stratix V Devices ^{(1), (2)} (Part 2 of 2)

Notes to Table 33:

(1) To achieve the maximum memory block performance, use a memory block clock that comes through global clock routing from an on-chip PLL set to **50**% output duty cycle. Use the Quartus II software to report timing for this and other memory block clocking schemes.

(2) When you use the error detection cyclical redundancy check (CRC) feature, there is no degradation in F_{MAX}.

(3) The F_{MAX} specification is only achievable with Fitter options, MLAB Implementation In 16-Bit Deep Mode enabled.

Temperature Sensing Diode Specifications

Table 34 lists the internal TSD specification.

Table 34. Internal Temperature Sensing Diode Specification

Temperature Range	Accuracy	Offset Calibrated Option	Sampling Rate	Conversion Time	Resolution	Minimum Resolution with no Missing Codes
-40°C to 100°C	±8°C	No	1 MHz, 500 KHz	< 100 ms	8 bits	8 bits

Table 35 lists the specifications for the Stratix V external temperature sensing diode.

Table 35.	External	Temperature	Sensing Dic	de Specifica	ations for Stratix	V Devices
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Description	Min	Тур	Max	Unit
I _{bias} , diode source current	8	—	200	μA
V _{bias,} voltage across diode	0.3	—	0.9	V
Series resistance	—	_	< 1	Ω
Diode ideality factor	1.006	1.008	1.010	_

Speed Grade	Min	Max	Unit
C4,I4	8	16	ps

Table 40. DQS Phase Offset Delay Per Setting for Stratix V Devices ^{(1), (2)} (Part 2 of 2)

Notes to Table 40:

(1) The typical value equals the average of the minimum and maximum values.

(2) The delay settings are linear with a cumulative delay variation of 40 ps for all speed grades. For example, when using a -2 speed grade and applying a 10-phase offset setting to a 90° phase shift at 400 MHz, the expected average cumulative delay is [625 ps + (10 × 10 ps) ± 20 ps] = 725 ps ± 20 ps.

Table 41 lists the DQS phase shift error for Stratix V devices.

Table 41. DQS Phase Shift Error Specification for DLL-Delayed Clock (t_{DQS_PSERR}) for Stratix V Devices ⁽¹⁾

Number of DQS Delay Buffers	C1	C2, C2L, I2, I2L	C3, I3, I3L, I3YY	C4,14	Unit
1	28	28	30	32	ps
2	56	56	60	64	ps
3	84	84	90	96	ps
4	112	112	120	128	ps

Notes to Table 41:

(1) This error specification is the absolute maximum and minimum error. For example, skew on three DQS delay buffers in a -2 speed grade is ± 78 ps or ± 39 ps.

Table 42 lists the memory output clock jitter specifications for Stratix V devices.

Table 42. Memory Output Clock Jitter Specification for Stratix V Devices (1	^{),} (Part 1 of 2) ^{(2), (3)}
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Clock Natural Parameter		Symbol	C1		C2, C2L, I2, I2L		C3, I3, I3L, I3YY		C4,14		Unit
NELWURK			Min	Max	Min	Max	Min	Max	Min	Max	
	Clock period jitter	$t_{JIT(per)}$	-50	50	-50	50	-55	55	-55	55	ps
Regional	Cycle-to-cycle period jitter	$t_{\text{JIT(cc)}}$	-100	100	-100	100	-110	110	-110	110	ps
	Duty cycle jitter	$t_{JIT(duty)}$	-50	50	-50	50	-82.5	82.5	-82.5	82.5	ps
	Clock period jitter	$t_{JIT(per)}$	-75	75	-75	75	-82.5	82.5	-82.5	82.5	ps
Global	Cycle-to-cycle period jitter	$t_{\text{JIT(cc)}}$	-150	150	-150	150	-165	165	-165	165	ps
	Duty cycle jitter	$t_{JIT(duty)}$	-75	75	-75	75	-90	90	-90	90	ps

Duty Cycle Distortion (DCD) Specifications

Table 44 lists the worst-case DCD for Stratix V devices.

Table 44. Worst-Case DCD on Stratix V I/O Pins (1)

Symbol	C	1	C2, C2	L, 12, 12L	C3, I I3	3, I3L, IYY	C4	4,14	Unit
-	Min	Max	Min	Max	Min	Max	Min	Max	
Output Duty Cycle	45	55	45	55	45	55	45	55	%

Note to Table 44:

(1) The DCD numbers do not cover the core clock network.

Configuration Specification

POR Delay Specification

Power-on reset (POR) delay is defined as the delay between the time when all the power supplies monitored by the POR circuitry reach the minimum recommended operating voltage to the time when the nSTATUS is released high and your device is ready to begin configuration.



For more information about the POR delay, refer to the *Hot Socketing and Power-On Reset in Stratix V Devices* chapter.

Table 45 lists the fast and standard POR delay specification.

Table 45. Fast and Standard POR Delay Specification (1)

POR Delay	Minimum	Maximum	
Fast	4 ms	12 ms	
Standard	100 ms	300 ms	

Note to Table 45:

(1) You can select the POR delay based on the MSEL settings as described in the MSEL Pin Settings section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.

JTAG Configuration Specifications

Table 46 lists the JTAG timing parameters and values for Stratix V devices.

Table 46. JTAG Timing Parameters and Values for Stratix V Devices

Symbol	Description	Min	Max	Unit
t _{JCP}	TCK clock period ⁽²⁾	30		ns
t _{JCP}	TCK clock period ⁽²⁾	167	—	ns
t _{JCH}	TCK clock high time ⁽²⁾	14	—	ns
t _{JCL}	TCK clock low time ⁽²⁾	14		ns
t _{JPSU (TDI)}	TDI JTAG port setup time	2	—	ns
t _{JPSU (TMS)}	TMS JTAG port setup time	3	_	ns

	Mombor	Active Serial ⁽¹⁾			Fast Passive Parallel ⁽²⁾		
Variant	Code	Width	DCLK (MHz)	Min Config Time (s)	Width	DCLK (MHz)	Min Config Time (s)
	D3	4	100	0.344	32	100	0.043
	D4	4	100	0.534	32	100	0.067
	D4	4	100	0.344	32	100	0.043
03	D5	4	100	0.534	32	100	0.067
	D6	4	100	0.741	32	100	0.093
	D8	4	100	0.741	32	100	0.093
E	E9	4	100	0.857	32	100	0.107
	EB	4	100	0.857	32	100	0.107

Table 48. Minimum Configuration Time Estimation for Stratix V Devices

Notes to Table 48:

(1) DCLK frequency of 100 MHz using external CLKUSR.

(2) Max FPGA FPP bandwidth may exceed bandwidth available from some external storage or control logic.

Fast Passive Parallel Configuration Timing

This section describes the fast passive parallel (FPP) configuration timing parameters for Stratix V devices.

DCLK-to-DATA[] Ratio for FPP Configuration

FPP configuration requires a different DCLK-to-DATA[]ratio when you enable the design security, decompression, or both features. Table 49 lists the DCLK-to-DATA[]ratio for each combination.

Configuration Scheme	Decompression	Design Security	DCLK-to-DATA[] Ratio
	Disabled	Disabled	1
	Disabled	Enabled	1
FFF XO	Enabled	Disabled	2
	Enabled	Enabled	2
	Disabled	Disabled	1
	Disabled	Enabled	2
FFF ×10	Enabled	Disabled	4
	Enabled	Enabled	4

 Table 49. DCLK-to-DATA[] Ratio ⁽¹⁾ (Part 1 of 2)

Configuration Scheme	Decompression	Design Security	DCLK-to-DATA[] Ratio
	Disabled	Disabled	1
	Disabled	Enabled	4
FPP ×32	Enabled	Disabled	8
	Enabled	Enabled	8

Table 49.	DCLK-to-DATA[]	Ratio ⁽¹⁾	(Part 2 of 2)
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Note to Table 49:

(1) Depending on the DCLK-to-DATA [] ratio, the host must send a DCLK frequency that is r times the data rate in bytes per second (Bps), or words per second (Wps). For example, in FPP ×16 when the DCLK-to-DATA [] ratio is 2, the DCLK frequency must be 2 times the data rate in Wps. Stratix V devices use the additional clock cycles to decrypt and decompress the configuration data.

Figure 11 shows the configuration interface connections between the Stratix V device and a MAX II or MAX V device for single device configuration.

Figure 11. Single Device FPP Configuration Using an External Host



Notes to Figure 11:

- (1) Connect the resistor to a supply that provides an acceptable input signal for the Stratix V device. V_{CCPGM} must be high enough to meet the V_{IH} specification of the I/O on the device and the external host. Altera recommends powering up all configuration system I/Os with V_{CCPGM} .
- (2) You can leave the nCEO pin unconnected or use it as a user I/O pin when it does not feed another device's nCE pin.
- (3) The MSEL pin settings vary for different data width, configuration voltage standards, and POR delay. To connect MSEL, refer to the MSEL Pin Settings section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (4) If you use FPP ×8, use DATA [7..0]. If you use FPP ×16, use DATA [15..0].

IF the DCLK-to-DATA[] ratio is greater than 1, at the end of configuration, you can only stop the DCLK (DCLK-to-DATA[] ratio – 1) clock cycles after the last data is latched into the Stratix V device.

Active Serial Configuration Timing

Table 52 lists the DCLK frequency specification in the AS configuration scheme.

Fable 52.	DCLK Frequency	Specification in th	e AS Configuration	Scheme ^{(1),}	(2)
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Minimum	Typical	Maximum	Unit
5.3	7.9	12.5	MHz
10.6	15.7	25.0	MHz
21.3	31.4	50.0	MHz
42.6	62.9	100.0	MHz

Notes to Table 52:

(1) This applies to the DCLK frequency specification when using the internal oscillator as the configuration clock source.

(2) The AS multi-device configuration scheme does not support DCLK frequency of 100 MHz.

Figure 14 shows the single-device configuration setup for an AS ×1 mode.





Notes to Figure 14:

- (1) If you are using AS $\times 4$ mode, this signal represents the AS_DATA[3..0] and EPCQ sends in 4-bits of data for each DCLK cycle.
- (2) The initialization clock can be from internal oscillator or CLKUSR pin.
- (3) After the option bit to enable the INIT_DONE pin is configured into the device, the INIT_DONE goes low.

Table 53 lists the timing parameters for AS $\times 1$ and AS $\times 4$ configurations in Stratix V devices.

Table JS. As fining falancees for as $\times 1$ and as $\times 4$ configurations in straits V devices $(2, 2, 2, 3, 3, 3, 3, 3, 3, 3, 3, 3, 3, 3, 3, 3,$	Table 53.	AS Timing	Parameters for AS	\times 1 and AS \times 4 Confi	gurations in Stratix V	/ Devices ^{(1),} (2)	(Part 1 of 2)
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Symbol	Parameter	Minimum	Maximum	Units
t _{CO}	DCLK falling edge to AS_DATA0/ASDO output	—	2	ns
t _{SU}	Data setup time before falling edge on DCLK	1.5	_	ns
t _H	Data hold time after falling edge on DCLK	0	_	ns

Parameter	Availabla	Min	Fast Model		Slow Model							
(1)	Settings	Offset (2)	Industrial	Commercial	C1	C2	C3	C4	12	13, 13YY	14	Unit
D3	8	0	1.587	1.699	2.793	2.793	2.992	3.192	2.811	3.047	3.257	ns
D4	64	0	0.464	0.492	0.838	0.838	0.924	1.011	0.843	0.920	1.006	ns
D5	64	0	0.464	0.493	0.838	0.838	0.924	1.011	0.844	0.921	1.006	ns
D6	32	0	0.229	0.244	0.415	0.415	0.458	0.503	0.418	0.456	0.499	ns

Table 58.	IOE Pro	grammable De	ay for	Stratix V	V Devices	(Part 2 of 2)
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Notes to Table 58:

(1) You can set this value in the Quartus II software by selecting D1, D2, D3, D5, and D6 in the Assignment Name column of Assignment Editor.

(2) Minimum offset does not include the intrinsic delay.

Programmable Output Buffer Delay

Table 59 lists the delay chain settings that control the rising and falling edge delays of the output buffer. The default delay is 0 ps.

Symbol	Parameter	Typical	Unit
		0 (default)	ps
Dauman	Rising and/or falling edge25delay50	25	ps
DOUTBUF		50	ps
		75	ps

Note to Table 59:

(1) You can set the programmable output buffer delay in the Quartus II software by setting the Output Buffer Delay Control assignment to either positive, negative, or both edges, with the specific values stated here (in ps) for the Output Buffer Delay assignment.

Glossary

Table 60 lists the glossary for this chapter.

Table 60. Glossary (Part 1 of 4)

Letter	Subject Definitions			
Α				
В	—	—		
С				
D	—	_		
E	— — —			
	f _{HSCLK}	Left and right PLL input clock frequency.		
F	f _{HSDR}	High-speed I/O block—Maximum and minimum LVDS data transfer rate (f _{HSDR} = 1/TUI), non-DPA.		
	f _{hsdrdpa}	High-speed I/O block—Maximum and minimum LVDS data transfer rate (f _{HSDRDPA} = 1/TUI), DPA.		

Table 60.	Glossary	(Part 3 of 4)
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Letter	Subject	Definitions					
	SW (sampling window)	Timing Diagram—the period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window, as shown: Bit Time 0.5 x TCCS RSKM Sampling Window RSKM 0.5 x TCCS RSKM					
S	Single-ended voltage referenced I/O standard	The JEDEC standard for SSTL and HSTL I/O defines both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing: <i>Single-Ended Voltage Referenced I/O Standard</i> 					
	t _C	High-speed receiver and transmitter input and output clock period.					
	TCCS (channel- to-channel-skew)	The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew, across channels driven by the same PLL. The clock is included in the TCCS measurement (refer to the <i>Timing Diagram</i> figure under SW in this table).					
		High-speed I/O block—Duty cycle on the high-speed transmitter output clock.					
т	t _{DUTY}	Timing Unit Interval (TUI) The timing budget allowed for skew, propagation delays, and the data sampling window.					
		$(TUI = 1/(receiver input clock frequency multiplication factor) = t_c/w)$					
	t _{FALL}	Signal high-to-low transition time (80-20%)					
	t _{INCCJ}	Cycle-to-cycle jitter tolerance on the PLL clock input.					
	t _{outpj_i0}	Period jitter on the general purpose I/O driven by a PLL.					
	t _{outpj_dc}	Period jitter on the dedicated clock output driven by a PLL.					
	t _{RISE}	Signal low-to-high transition time (20-80%)					
U		_					

Table 61. Document Revision History (Part 2 of 3)

Date	Version	Changes
		 Added the I3YY speed grade and changed the data rates for the GX channel in Table 1.
		 Added the I3YY speed grade to the V_{CC} description in Table 6.
		 Added the I3YY speed grade to V_{CCHIP_L}, V_{CCHIP_R}, V_{CCHSSI_L}, and V_{CCHSSI_R} descriptions in Table 7.
		■ Added 240-Ω to Table 11.
		Changed CDR PPM tolerance in Table 23.
		 Added additional max data rate for fPLL in Table 23.
		 Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 25.
		 Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 26.
		 Changed CDR PPM tolerance in Table 28.
		 Added additional max data rate for fPLL in Table 28.
		 Changed the mode descriptions for MLAB and M20K in Table 33.
		 Changed the Max value of f_{HSCLK_OUT} for the C2, C2L, I2, I2L speed grades in Table 36.
November 2014	3.3	 Changed the frequency ranges for C1 and C2 in Table 39.
		 Changed the .rbf file sizes for 5SGSD6 and 5SGSD8 in Table 47.
		 Added note about nSTATUS to Table 50, Table 51, Table 54.
		 Changed the available settings in Table 58.
		 Changed the note in "Periphery Performance".
		 Updated the "I/O Standard Specifications" section.
		 Updated the "Raw Binary File Size" section.
		 Updated the receiver voltage input range in Table 22.
		 Updated the max frequency for the LVDS clock network in Table 36.
		■ Updated the DCLK note to Figure 11.
		 Updated Table 23 VO_{CM} (DC Coupled) condition.
		Updated Table 6 and Table 7.
		 Added the DCLK specification to Table 55.
		Updated the notes for Table 47.
		 Updated the list of parameters for Table 56.
November 2013	3.2	Updated Table 28
November 2013	3.1	Updated Table 33
November 2013	3.0	Updated Table 23 and Table 28
October 2013	2.9	 Updated the "Transceiver Characterization" section
		 Updated Table 3, Table 12, Table 14, Table 19, Table 20, Table 23, Table 24, Table 28, Table 30, Table 31, Table 32, Table 33, Table 36, Table 39, Table 40, Table 41, Table 42, Table 47, Table 53, Table 58, and Table 59
Uctober 2013	2.8	 Added Figure 1 and Figure 3
		 Added the "Transceiver Characterization" section
		 Removed all "Preliminary" designations.